

### MDF5N50-VB Datasheet

# N-Channel 650V (D-S) Power MOSFET

PRODUCT SUMMARY							
	V <sub>DS</sub> (V) at T <sub>J</sub> max.	650	)				
	R <sub>DS(on)</sub> at 25 °C (Ω)	V <sub>GS</sub> = 10 V	1.1				
	Q <sub>g</sub> max. (nC)	25					
	Q <sub>gs</sub> (nC)	2.0	)				
	Q <sub>gd</sub> (nC)	2.7					
	Configuration	Single					

Top View

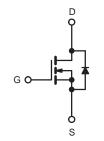
**TO-220 FULLPAK** 

#### **FEATURES**

- Low figure-of-merit (FOM) Ron x Qa
- Low input capacitance (Ciss)
- · Reduced switching and conduction losses
- Ultra low gate charge (Qq)
- Avalanche energy rated (UIS)

#### **APPLICATIONS**

- Server and telecom power supplies
- Switch mode power supplies (SMPS)
- Power factor correction power supplies (PFC)
- - High-intensity discharge (HID)
  - Fluorescent ballast lighting
- Industrial



N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (T <sub>C</sub> = 25 °C, unless otherwise noted)							
PARAMETER			SYMBOL	LIMIT	UNIT		
Drain-Source Voltage	Drain-Source Voltage			650	V		
Gate-Source Voltage	Gate-Source Voltage			± 30	V		
Continuous Drain Current (T.I = 150 °C)	V <sub>GS</sub> at 10 V	T <sub>C</sub> = 25 °C	l <sub>D</sub>	7.0			
Continuous Drain Current (1) = 130 C)		T <sub>C</sub> = 100 °C		5.6	Α		
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	28			
Linear Derating Factor Single Pulse Avalanche Energy b Maximum Power Dissipation Operating Junction and Storage Temperature Range				1.67/1.5/0.3	W/°C		
			E <sub>AS</sub>	86	mJ		
			$P_{D}$	83/83/31	W		
			T <sub>J</sub> , T <sub>stg</sub>	-55 to +150	°C		
Drain-Source Voltage Slope	T <sub>J</sub> = 125 °C		dV/dt	50	1//22		
Reverse Diode dV/dt <sup>d</sup>			av/at	4.5	- V/ns		
Soldering Recommendations (Peak Temperature) c	for 10 s			300	°C		

- a. Repetitive rating; pulse width limited by maximum junction temperature. b.  $V_{DD}=50$  V, starting  $T_J=25$  °C, L=28.2 mH,  $R_g=25$   $\Omega$ ,  $I_{AS}=3.5$  A.

- c. 1.6 mm from case. d.  $I_{SD} \le I_D$ , dl/dt = 100 A/ $\mu$ s, starting  $T_J = 25$  °C.



THERMAL RESISTANCE RATI	NGS			
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R <sub>thJA</sub>	-	63	°C/W
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	-	0.6	C/ VV

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static				•	,		
Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>GS</sub> =	= 0 V, I <sub>D</sub> = 250 μA	650	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	e to 25 °C, I <sub>D</sub> = 1 mA	-	0.65	-	V/°C
Gate-Source Threshold Voltage (N)	V <sub>GS(th)</sub>	V <sub>DS</sub> =	· V <sub>GS</sub> , I <sub>D</sub> = 250 μA	2.5	-	5	V
		,	V <sub>GS</sub> = ± 20 V	-	-	± 100	nA
Gate-Source Leakage	$I_{GSS}$		$V_{GS} = \pm 30 \text{ V}$	-	-	± 1	μA
			: 650 V, V <sub>GS</sub> = 0 V	-	-	1	<del>                                     </del>
Zero Gate Voltage Drain Current	$I_{DSS}$		', V <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C	-	-	10	μA
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 4 A	-	1.1	-	Ω
Forward Transconductance	9 <sub>fs</sub>		= 30 V, I <sub>D</sub> = 4 A	-	16	-	S
Dynamic		_			ı	ı	
Input Capacitance	C <sub>iss</sub>		V0.V	-	860	-	T
Output Capacitance	C <sub>oss</sub>	1	$V_{GS} = 0 \text{ V},$ $V_{DS} = 100 \text{ V},$ f = 1  MHz		120	-	pF
Reverse Transfer Capacitance	C <sub>rss</sub>	7			15	-	
Effective Output Capacitance, Energy Related <sup>a</sup>	C <sub>o(er)</sub>	V <sub>DS</sub> = 0 V to 520 V, V <sub>GS</sub> = 0 V		-	45	-	
Effective Output Capacitance, Time Related <sup>b</sup>	C <sub>o(tr)</sub>			-	62	-	
Total Gate Charge	Qg			-	25		
Gate-Source Charge	Q <sub>gs</sub>	V <sub>GS</sub> = 10 V	$V_{GS} = 10 \text{ V}$ $I_{D} = 4 \text{ A}, V_{DS} = 520 \text{ V}$	-	2.0	-	nC
Gate-Drain Charge	Q <sub>gd</sub>	1			2.7	-	1
Turn-On Delay Time	t <sub>d(on)</sub>			-	25	-	ns
Rise Time	t <sub>r</sub>	Von	$V_{DD} = 520 \text{ V}, I_D = 4 \text{ A}, V_{GS} = 10 \text{ V}, R_a = 9.1 \Omega$		55	-	
Turn-Off Delay Time	t <sub>d(off)</sub>	00			70	-	
Fall Time	t <sub>f</sub>			-	40	-	
Gate Input Resistance	R <sub>g</sub>	f = 1 MHz, open drain		-	3.5	-	Ω
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET syml	MOSFET symbol showing the		-	7	
Pulsed Diode Forward Current	I <sub>SM</sub>	integral reverse p - n junction diode		-	-	18	_ A
Diode Forward Voltage	V <sub>SD</sub>	T <sub>J</sub> = 25 °C, I <sub>S</sub> = 4 A, V <sub>GS</sub> = 0 V		-	-	1.5	V
Reverse Recovery Time	t <sub>rr</sub>			-	190	-	ns
Reverse Recovery Charge	Q <sub>rr</sub>	$T_J = 25$ °C, $I_F = I_S = 4$ A, $dI/dt = 100$ A/ $\mu$ s, $V_R = 400$ V		-	2.3	-	μC
Reverse Recovery Current	I <sub>RRM</sub>			_	10	_	A

#### Notes

- a.  $C_{oss(er)}$  is a fixed capacitance that gives the same energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ . b.  $C_{oss(tr)}$  is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ .



#### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

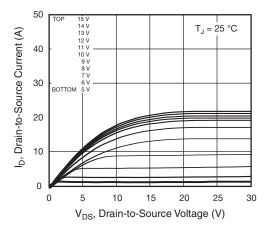


Fig. 1 - Typical Output Characteristics

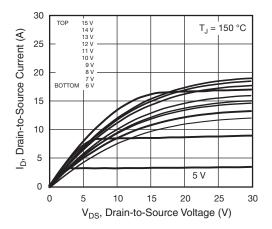


Fig. 2 - Typical Output Characteristics

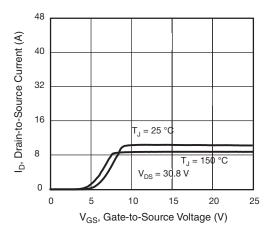


Fig. 3 - Typical Transfer Characteristics

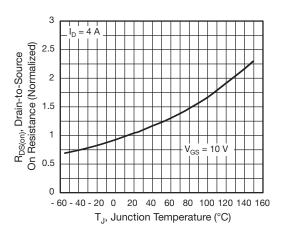


Fig. 4 - Normalized On-Resistance vs. Temperature

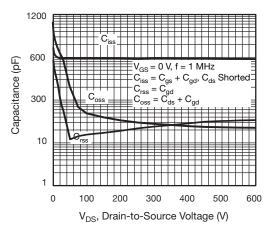


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

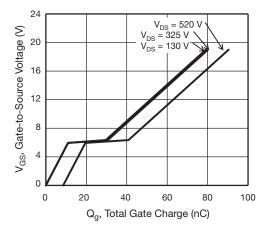


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage



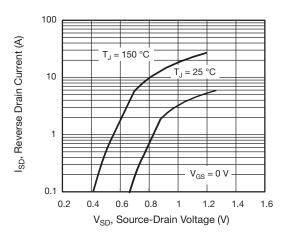


Fig. 7 - Typical Source-Drain Diode Forward Voltage

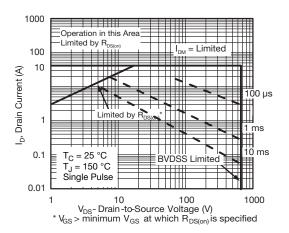


Fig. 8 - Maximum Safe Operating Area

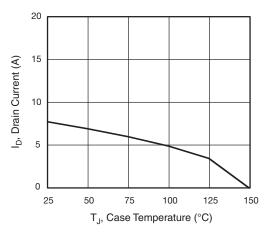


Fig. 9 - Maximum Drain Current vs. Case Temperature

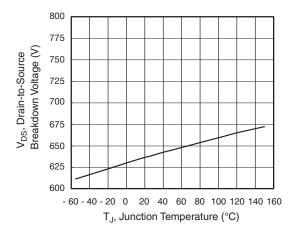


Fig. 10 - Temperature vs. Drain-to-Source Voltage

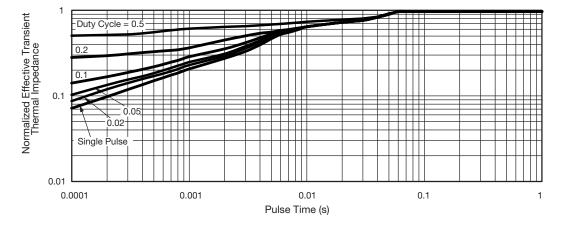


Fig. 11 - Normalized Thermal Transient Impedance, Junction-to-Case



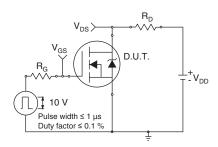


Fig. 12 - Switching Time Test Circuit

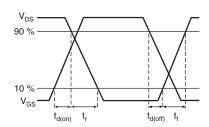


Fig. 13 - Switching Time Waveforms

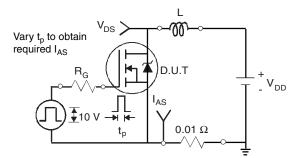


Fig. 14 - Unclamped Inductive Test Circuit

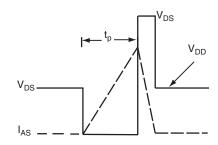


Fig. 15 - Unclamped Inductive Waveforms

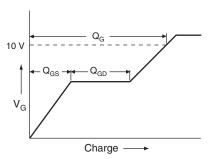


Fig. 16 - Basic Gate Charge Waveform

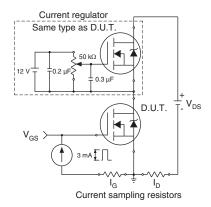
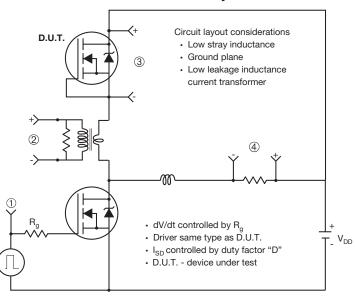


Fig. 17 - Gate Charge Test Circuit

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#### Peak Diode Recovery dV/dt Test Circuit



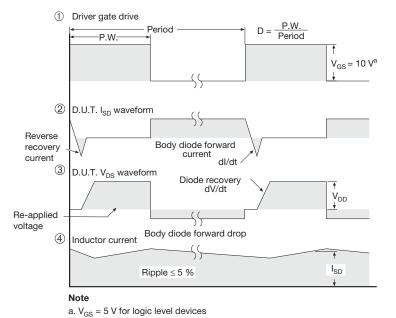
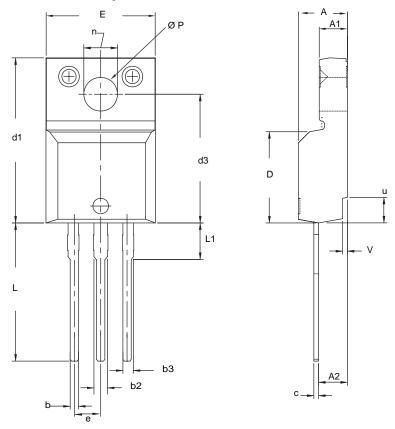


Fig. 18 - For N-Channel

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#### **TO-220 FULLPAK (HIGH VOLTAGE)**



	MILLIN	METERS	INCHES	
DIM.	MIN.	MAX.	MIN.	MAX.
А	4.570	4.830	0.180	0.190
A1	2.570	2.830	0.101	0.111
A2	2.510	2.850	0.099	0.112
b	0.622	0.890	0.024	0.035
b2	1.229	1.400	0.048	0.055
b3	1.229	1.400	0.048	0.055
С	0.440	0.629	0.017	0.025
D	8.650	9.800	0.341	0.386
d1	15.88	16.120	0.622	0.635
d3	12.300	12.920	0.484	0.509
E	10.360	10.630	0.408	0.419
е	2.54	4 BSC 0.100 BSC		BSC
L	13.200	13.730	0.520	0.541
L1	3.100	3.500	0.122	0.138
n	6.050	6.150	0.238	0.242
ØΡ	3.050	3.450	0.120	0.136
u	2.400	2.500	0.094	0.098
V	0.400	0.500	0.016	0.020

#### Notes

- To be used only for process drawing.
   These dimensions apply to all TO-220, FULLPAK leadframe versions 3 leads.
   All critical dimensions should C meet C<sub>pk</sub> > 1.33.
   All dimensions include burrs and plating thickness.

- 5. No chipping or package damage.



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